

<b>Notice of References Cited</b>	Application/Control No. 10/617,015		Applicant(s)/Patent Under Reexamination CHEN, YINGJIAN	
	Examiner BRIAN E. MILLER		Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0087130 A1	05-2003	Sugawara, Takahiko	428/692
*	B	US-6,828,039 B2	12-2004	Sugawara, Takahiko	428/621
*	C	US-7,215,516 B2	05-2007	Yoshikawa et al.	360/324.11
*	D	US-5,424,054	06-1995	Bethune et al.	423/447.2
*	E	US-6,876,574	04-2005	Giebel et al.	365/158
*	F	US-7,379,326	05-2008	Ushida et al.	365/158
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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